

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 09/885,701 | Applicant(s)/Patent Under Reexamination YAK ET AL. | |
| | Examiner Bach Q Vuong | Art Unit 2653 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-5,341,353 | 08-1994 | Yoshio et al. | 369/44.28 |
| | B | US-6,320,831 | 11-2001 | Inoue et al. | 369/47.22 |
| | C | US-6,504,799 | 01-2003 | Yamashita et al. | 369/44.11 |
| | D | US-6,721,242 | 04-2004 | Ohnishi et al. | 369/44.26 |
| | E | US-6,091,685 | 07-2000 | Kim, Dae Young | 369/47.51 |
| | F | US-6,594,210 | 07-2003 | Kumagai, Eiji | 369/47.17 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

